SCAS518A - JULY 1995 - REVISED APRIL 1996

- Inputs Are TTL-Voltage Compatible
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), DIP (N) Packages, Ceramic Chip Carriers (FK), Flat (W), and DIP (J) Packages

description

The 'ACT04 contain six independent inverters. The devices perform the Boolean function $Y = \overline{A}$.

The SN54ACT04 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ACT04 is characterized for operation from -40°C to 85°C.

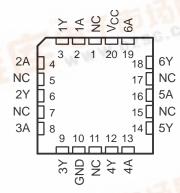
FUNCTION TABLE (each inverter)

INPUT A	OUTPUT
H W	MAF
L	Н

SN54ACT04...J OR W PACKAGE SN74ACT04...D, DB, N, OR PW PACKAGE (TOP VIEW)



SN54ACT04 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

logic diagram, each inverter (positive logic)



logic symbol†

1A	1	1	2 1	Υ
	3	<u> </u>	4	
2A	5		6	Y
3A	9	ーカナリ	8	Y
4A	11	O. WWW.D.	10	Y
5A 6A	13		12	Ϋ́

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, DB, J, N, PW, and W packages.

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SN54ACT04, SN74ACT04 HEX INVERTERS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}		0.5 V to 7 V
Input voltage range, V _I (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V _O (see Note 1)		$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)		±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})		±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})		±50 mA
Continuous current through V _{CC} or GND		±200 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2):	D package	1.25 W
	DB package	0.5 W
	N package	1.1 W
	PW package	0.5 W
Storage temperature range, T _{stg}		−65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.

recommended operating conditions (see Note 3)

		SN54A	CT04	SN74A	UNIT	
		MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
V _I L	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	VCC	0	VCC	V
VO	Output voltage	0	VCC	0	VCC	V
IOH	High-level output current		- 24		- 24	mA
loL	Low-level output current		24		24	mA
Δt/Δν	Input transition rise or fall rate	0	8	0	8	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS VC		Т	A = 25°C	;	SN54ACT04		SN74ACT04		UNIT
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
	10.1 FO.1.A	4.5 V	4.4	4.49		4.4		4.4		
	ΙΟΗ = – 50 μΑ	5.5 V	5.4	5.49		5.4		5.4		
Vou		4.5 V	3.86			3.7		3.76		V
Voн	$I_{OL} = -24 \text{ mA}$	5.5 V	4.86			4.7		4.76		V
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85		
	$I_{OL} = 50 \mu A$ $I_{OL} = 24 \text{ mA}$	4.5 V		0.001	0.1		0.1		0.1	V
		5.5 V		0.001	0.1		0.1		0.1	
\/o		4.5 V			0.36		0.5		0.44	
VOL		5.5 V			0.36		0.5		0.44	
	I _{OL} = 50 mA [†]	5.5 V					1.65			
	I _{OL} = 75 mA [†]	5.5 V							1.65	
lį	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			2		40		20	μΑ
Δlcc [‡]	One input at 3.4 V, Other inputs at GND or V _{CC}	5.5 V		0.6			1.6		1.5	mA
C _i	$V_I = V_{CC}$ or GND	5 V		4.5						pF

Thot more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

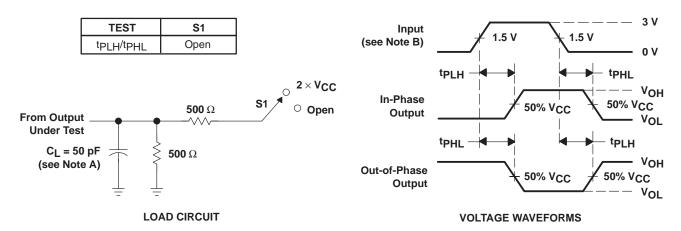
PARAMETER	FROM	то	T,	Վ = 25° C	;	SN54A	CT04	SN74A	CT04	UNIT
	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
t _{PLH}	А	V	1	6	8.5	1	9	1	9	ns
tPHL		ī	1	5.5	8	1	8.5	1	8.5	115

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CON	TYP	UNIT	
C _{pd}	Power dissipation capacitance	C _L = 50 pF,	f = 1 MHz	45	pF

[‡] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f \leq 2.5 \ ns$, $t_f \leq 2.5 \ ns$.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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